

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SAKAI ET AL.	
		Examiner Howard Weiss	Art Unit 2814	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,943,376	09-2005	Nakatsuka et al.	257/77
B	US-			
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E	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.